Notice of References Cited Application/Control No. 10/594,549 Examiner Sharidan Carrillo Applicant(s)/Patent Under Reexamination OHNO ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,882,433	03-1999	Ueno, Kinya	134/31
*	В	US-6,334,902	01-2002	Mertens et al.	134/1
*	С	US-6,770,151	08-2004	Ravkin et al.	134/33
*	D	US-2003/0192577	10-2003	Thakur et al.	134/146
*	Е	US-2003/0079764	05-2003	Hirose et al.	134/95.3
*	F	US-2003/0022515	01-2003	Nakagawa, Seiji	438/734
*	G	US-2004/0074526	04-2004	Aoki et al.	134/036
*	Ι	US-2004/0040177	03-2004	Izumi, Akira	034/492
*	I	US-2006/0081269	04-2006	Kim et al.	134/002
*	J	US-2006/0048792	03-2006	Nakamura et al.	134/002
*	K	US-2006/0266389	11-2006	Thakur et al.	134/094.1
*	L	US-2008/0251101	10-2008	Ohno et al.	134/4
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν	JP2002-057088	02-2002	Japan	Shunichi	
	0					
	Ρ					
	σ					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.